

Amendments to the Claims:

This listing of claims replaces all prior versions and listings of claims in the application:

Listing of Claims:

1. (Currently Amended) An apparatus comprising:
a charge pump having a capacity that is preset to a particular value; and
a measuring circuit including a voltage sensor to sense a voltage at an input and output of the charge pump and a temperature sensor to measure the temperature of the charge pump, wherein the measuring circuit is configured to measure an actual capacity of the charge pump and to reset the capacity of the charge pump to a value based on the measured capacity.
2. (Original) The apparatus of claim 1 wherein an output of the charge pump is preset to operate at particular voltage and current levels.
3. (Canceled) The apparatus of claim 1 wherein the measuring circuit includes a temperature sensor.
4. (Canceled) The apparatus of claim 1 wherein the measuring circuit includes a voltage sensor to sense a voltage at an input of the charge pump.
5. (Canceled) The apparatus of claim 1 wherein the measuring circuit includes a voltage sensor to sense a voltage at an output of the charge pump.
6. (Original) The apparatus of claim 1 wherein the measuring circuit includes a current sensor to sense a current at an output of the charge pump.
7. (Currently Amended) An apparatus comprising:
an array of memory cells; and

a charge pump circuit coupled to the array of memory cells to drive the array of memory cells, the charge pump circuit comprising:

a charge pump having a capacity that is preset to a particular value, and
a measuring circuit including a voltage sensor to sense a voltage at an input and output of the charge pump and a temperature sensor to measure the temperature of the charge pump, wherein the measuring circuit is configured to measure an actual capacity of the charge pump and to reset the capacity of the charge pump to a value based on the measured capacity.

8. (Original) The apparatus of claim 7 wherein an output of the charge pump is preset to operate at particular voltage and current levels.

9. (Canceled) The apparatus of claim 7 wherein the measuring circuit includes a temperature sensor.

10. (Canceled) The apparatus of claim 7 wherein the measuring circuit includes a voltage sensor to sense a voltage at an input of the charge pump.

11. (Canceled) The apparatus of claim 7 wherein the measuring circuit includes a voltage sensor to sense the voltage at an output of the charge pump.

12. (Original) The apparatus of claim 7 wherein the measuring circuit includes a current sensor to sense a current at an output of the charge pump.

13. (Currently Amended) A computer system comprising:

a central processor; and

a memory coupled to the central processor, the memory comprising:

an array of memory cells, and

a charge pump circuit coupled to the array of memory cells to drive the array of memory cells, the charge pump circuit comprising:

a charge pump having a capacity that is preset to a particular value, and

a measuring circuit including a voltage sensor to sense a voltage at an input and output of the charge pump and a temperature sensor to measure the temperature of the charge pump, wherein the measuring circuit is configured to measure an actual capacity of the charge pump and to reset the capacity of the charge pump to a value based on the measured capacity.

14. (Original) The computer system of claim 13 wherein an output of the charge pump is preset to operate at particular voltage and current levels.

15. (Canceled) The computer system of claim 13 wherein the measuring circuit includes a temperature sensor.

16. (Canceled) The computer system of claim 13 wherein the measuring circuit includes a voltage sensor to sense a voltage at an input of the charge pump.

17. (Canceled) The computer system of claim 13 wherein the measuring circuit includes a voltage sensor to sense a voltage at an output of the charge pump.

18. (Original) The computer system of claim 13 wherein the measuring circuit includes a current sensor to sense the current at an input of the charge pump.

19. (Currently amended) A method comprising:
measuring a capacity of a charge pump wherein measuring includes sensing a voltage at an input and output of the charge pump using a voltage sensor, and measuring the temperature of the charge pump using a temperature sensor; and
resetting the capacity of the charge pump to a value based on the measured capacity.

20. (Original) The method of claim 19 further comprising presetting a capacity of the charge pump to a particular value.

21. (Original) The method of claim 20 wherein presetting a capacity of the charge pump to a particular value includes presetting the charge pump to particular voltage and current levels.

22. (Canceled) The method of claim 19 wherein measuring the capacity of the charge pump includes measuring a temperature of the charge pump.

23. (Canceled) The method of claim 19 wherein measuring the capacity of the charge pump includes measuring a voltage at an input of the charge pump.

24. (Canceled) The method of claim 19 wherein measuring the capacity of the charge pump includes measuring a voltage at an output of the charge pump.

25. (Original) The method of claim 19 wherein measuring the capacity of the charge pump includes measuring a current at an output of the charge pump.